



PRODUCT BULLETIN # 20482

Generic Copy

Issue Date: 28-May-2014

TITLE: NCP551, NCV551 DATASHEET SPECIFICATION UPDATE

PROPOSED FIRST SHIP DATE: 28-Aug-2014

AFFECTED CHANGE CATEGORY(S): Datasheet

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor sales office or <Bett.Lofts@onsemi.com>

NOTIFICATION TYPE:

ON Semiconductor considers this change approved unless specific conditions of acceptance are provided in writing. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

Modification is made on page 3 in the ELECTRICAL CHARACTERISTICS table of the NCP551/D datasheet, Quiescent Current Test V_{in} condition change. The updated V_{in} Condition of I_Q test parameter does not affect the device design, performance and application

See below the updated value highlighted in Red font.

FROM:

Quiescent Current (Enable Input = 0 V) (Enable Input = V_{in} , $I_{out} = 1.0$ mA to $I_{Q(nom.)}$)	I_Q	-	0.1	1.0	μA
		-	4.0	8.0	

TO:

Quiescent Current (Enable Input = 0 V) (Enable Input = V_{in} , $I_{out} = 1.0$ mA to $I_{Q(nom.)}$)	I_Q	-	0.1	1.0	μA
1.4V-2.0V ($V_{in}=4.0V$)		-	4.0	8.0	
2.1V-3.0V ($V_{in}=5.0V$)					
3.1V-4.0V ($V_{in}=6.0V$)					
4.1V-5.0V ($V_{in}=8.0V$)					

Purpose of change: Previous conditions did not permit sufficient input voltage for proper testing of the part Quiescent Current parameter.



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List of affected General Parts:

NCV551SN14T1G
NCV551SN15T1G
NCV551SN18T1G
NCV551SN25T1G
NCV551SN27T1G
NCV551SN28T1G
NCV551SN30T1G
NCV551SN31T1G
NCV551SN32T1G
NCV551SN33T1G
NCV551SN50T1G
NCP551SN15T1G
NCP551SN18T1G
NCP551SN25T1G
NCP551SN27T1G
NCP551SN28T1G
NCP551SN29T1G
NCP551SN30T1G
NCP551SN31T1G
NCP551SN32T1G
NCP551SN33T1G
NCP551SN50T1G